



# Certificate of Analysis

**ULTRAGrade™ Solution**  
**Aluminum ICP / ICP-MS Standard**  
**1000 µg/mL**

**Catalog Number:** ICP-013  
**Lot Number:** R00346  
**Job Number:** J00016190  
**Lot Issue Date:** 04/10/2013  
**Expiration Date:** 05/31/2020

**Starting Material:** aluminum nitrate nonahydrate  
**Starting Material Purity:** 99.998%  
**Starting Material Lot #:** BH01794  
**Matrix:** 2% nitric acid in low TOC water (< 50 ppb)  
**Atomic Weight Al:** 26.98

**Certified Value:** 1000 ± 2 µg/mL

This Certified Reference Material (CRM) was manufactured and verified in accordance with ULTRA's ISO 9001 registered quality system. The analyte concentration(s) were prepared and verified by an ISO Guide 34 / ISO 17025 accredited laboratory, and compared to calibration standards independently prepared using NIST SRM(s). The certified value and uncertainty value at the 95% confidence level for each analyte is determined gravimetrically.

**Classical Wet Assay Method:** Theoretical, based on gravimetric measurements

**Confirmation by Inductively Coupled Plasma Spectroscopy (ICP / ICP/MS) vs. NIST SRM 3101a**

ULTRA uses purified acids, 18 megohm double deionized water, calibrated Class A glassware & meticulously cleaned bottles in the manufacturing of ULTRAGrade standards. Balances used in the manufacturing of this standard are calibrated with weights traceable to NIST in compliance with ANSI/NCSL Z-540-1 and ISO 9001.

**Trace Metallic Impurities in Solution Standard in µg/mL:**

s	Al			*	Ga	<0.005	D	n	Nb			n	S		
*	Sb	<0.005	ND	n	Ge			n	Os			n	Ta		
*	As	<0.005	ND	n	Au			*	Pd	<0.005	ND	n	Te		
*	Ba	<0.005	ND	n	Hf			*	P	<0.005	ND	n	Tb		
*	Be	<0.005	ND	n	Ho			*	Pt	<0.005	ND	*	Tl	<0.005	ND
*	Bi	<0.005	ND	*	In	<0.005	ND	*	K	<0.005	ND	n	Th		
*	B	<0.005	ND	n	Ir			n	Pr			n	Tm		
*	Cd	<0.005	ND	*	Fe	<0.005	D	n	Re			*	Sn	<0.005	ND
*	Ca	<0.005	D	*	La	<0.005	ND	n	Rh			*	Ti	<0.005	ND
n	Ce			*	Pb	<0.005	ND	n	Rb			n	W		
n	Cs			*	Li	<0.005	ND	n	Ru			n	U		
*	Cr	<0.005	D	n	Lu			n	Sm			*	V	<0.005	D
*	Co	<0.005	ND	*	Mg	<0.005	ND	n	Sc			n	Yb		
*	Cu	<0.005	ND	*	Mn	<0.005	ND	n	Se	<0.005	ND	n	Y		
n	Dy			*	Hg	<0.005	ND	*	Si	<0.005	D	*	Zn	<0.005	ND
*	Er	<0.005	ND	*	Mo	<0.005	ND	*	Ag	<0.005	ND	n	Zr		
*	Eu	<0.005	ND	n	Nd			*	Na	<0.005	D				
*	Gd	<0.005	ND	*	Ni	<0.005	ND	*	Sr	<0.005	ND				

\* - element checked for  
ND - not detected

I - spectral interference  
D - detected

n - not checked for  
s - solution standard element

**Density of Solution (measured at 19.99°C ± 0.05°C):** 1.0157 g/mL



ISO 17025:2005  
Accredited  
A2LA  
Cert. No. 0851.01

ISO 9001:2000  
Registered  
TUV USA, Inc.  
Cert. No. 06-1004

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